Special Issue

Advanced Micro-Electro-Mechanical Systems and Micro-Electro-Optical-Mechanical Systems in Scanning Probe Microscopy

Message from the Guest Editor

The continuous evolution of micro-electro-mechanical systems (MEMSs) and micro-electro-optical-mechanical systems (MEOMSs) has significantly impacted the field of sensor design, offering unprecedented capabilities in precision sensing, actuation, and control. This Special Issue aims to provide a platform for researchers to share their latest findings, technological advancements, and innovative applications at the intersection of MEMSs/MEOMSs and scanning probe microscopy within the sensor community. Through this collection of contributions, we seek to foster collaboration, inspire new research directions, and propel the ongoing development of MEMS/MEOMS-based sensor technologies for SPM and beyond.

Guest Editor

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Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. Sensors organizes Special Issues devoted to specific sensing areas and applications each year.

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